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Space systems — Design qualification and acceptance tests of small spacecraft and units

Systèmes spatiaux — Qualification de la conception et essais de réception des petits véhicules spatiaux





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| Contents | | | | | |
|----------|----------------------|--------------------|--------------------------------------|------|--|
| Forev | word | | | vii | |
| Intro | ductio | l | | viii | |
| 1 | Scon | 1 | | 1 | |
| _ | _ | | | | |
| 2 | | | | | |
| 3 | Term | s and definitions | | 2 | |
| 4 | Abbr | Abbreviated terms | | | |
| 5 | General requirements | | | | |
| | 5.1 | | | | |
| | 5.2 | | | | |
| | 5.3 | | | | |
| | 5.4 | | | | |
| | 5.5 | | | | |
| | 5.6 | | on | | |
| | | 5.6.1 Test plan, | , specification and procedure | 5 | |
| | | | rt | | |
| | | | t for unit test results | | |
| | 5.7 | | olerances and accuracies | | |
| | 5.8 | | | | |
| | 5.9 | _ | n and testing philosophy | | |
| 6 | Satel | | | | |
| | 6.1 | | | | |
| | 6.2 | Test level and dur | ation | 8 | |
| 7 | Unit | ests | | 8 | |
| | 7.1 | | | | |
| | 7.2 | | | | |
| 8 | Test | equirements | | 17 | |
| O | 8.1 | | е | | |
| | 0.1 | | of test | | |
| | | | ties and setup as basic requirements | | |
| | | | le configuration | | |
| | | | ng during test | | |
| | | | s and duration | | |
| | | 8.1.6 Test cond | itions and guidelines | 18 | |
| | 8.2 | Functional test | | 18 | |
| | | | of test | 18 | |
| | | | ties and setup as basic requirements | | |
| | | | le configuration | | |
| | | | ng during test | | |
| | | | s and duration | | |
| | 0.0 | | litions and guidelines | | |
| | 8.3 | | | | |
| | | - | of test | | |
| | | | ties and setup as basic requirements | | |
| | | | le configuration | | |
| | | | ng during tests and duration | | |
| | | | s and durationlitions and guidelines | | |
| | 8.4 | | ose (TID) test | | |
| | 0.4 | | ose (TD) testof test | | |
| | | | ties and setup as basic requirements | | |
| | | | le configuration | | |
| | | citio restartic | | 20 | |

iii

| | 8.4.4 | Monitoring during test | 20 | | |
|------|---------|---|----|--|--|
| | 8.4.5 | Test levels and duration | 20 | | |
| | 8.4.6 | Test conditions and guidelines | 20 | | |
| 8.5 | Single | Event Effect (SEE) test | 20 | | |
| | 8.5.1 | Purpose of test | 20 | | |
| | 8.5.2 | Test facilities and setup as basic requirements | 20 | | |
| | 8.5.3 | Test article configuration | | | |
| | 8.5.4 | Monitoring during test | 21 | | |
| | 8.5.5 | Test levels and duration | 21 | | |
| | 8.5.6 | Test conditions and guidelines | 21 | | |
| | 8.5.7 | Test conditions and guidelines | 21 | | |
| 8.6 | Spacec | 21 | | | |
| | 8.6.1 | 8.6.1 Purpose of test | | | |
| | 8.6.2 | Test facilities and setup as basic requirements | 21 | | |
| | 8.6.3 | Test article configuration | 22 | | |
| | 8.6.4 | Monitoring during test | | | |
| | 8.6.5 | Test levels and duration | 22 | | |
| | 8.6.6 | Test conditions and guidelines | 22 | | |
| 8.7 | Electro | omagnetic Compatibility (EMC) test | 22 | | |
| | 8.7.1 | Purpose of test | | | |
| | 8.7.2 | Test facilities and setup as basic requirements | 22 | | |
| | 8.7.3 | Test article configuration | 22 | | |
| | 8.7.4 | Monitoring during test | 22 | | |
| | 8.7.5 | Test levels and duration | 23 | | |
| | 8.7.6 | Test conditions and guidelines | 23 | | |
| 8.8 | Deploy | ment test | | | |
| | 8.8.1 | Purpose of test | 23 | | |
| | 8.8.2 | Test facilities and setup as basic requirements | | | |
| | 8.8.3 | Test article configuration | | | |
| | 8.8.4 | Monitoring during test | | | |
| | 8.8.5 | Test levels and duration | | | |
| | 8.8.6 | Test conditions and guidelines | 23 | | |
| 8.9 | | tic field test | | | |
| 8.10 | | na pattern test | | | |
| 8.11 | | nent measurement | | | |
| 8.12 | | al property measurement | | | |
| 8.13 | | ner/Spacecraft interface test | | | |
| 8.14 | Quasi- | static load test | | | |
| | 8.14.1 | Purpose of test | | | |
| | 8.14.2 | Test facilities and setup as basic requirements | | | |
| | 8.14.3 | Test article configuration | | | |
| | 8.14.4 | Monitoring during test | | | |
| | 8.14.5 | Test levels and duration | | | |
| | 8.14.6 | Test conditions and guidelines | | | |
| 8.15 | | survey | | | |
| | 8.15.1 | Purpose of test | | | |
| | 8.15.2 | Test facilities and setup as basic requirements | | | |
| | 8.15.3 | Test article configuration | | | |
| | 8.15.4 | Monitoring during test | | | |
| | 8.15.5 | Test levels and duration | | | |
| | 8.15.6 | Test conditions and guidelines | | | |
| 8.16 | | idal vibration test | | | |
| | 8.16.1 | Purpose of test | | | |
| | 8.16.2 | Test facilities and setup as basic requirements | | | |
| | 8.16.3 | Test article configuration | | | |
| | 8.16.4 | Monitoring during test | | | |
| | 8.16.5 | Test levels and duration | | | |
| | 8.16.6 | Test conditions and guidelines | 26 | | |

| 8.17 | Randor | n vibration test | |
|------|---------|---|----|
| | 8.17.1 | Purpose of test | |
| | 8.17.2 | Test facilities and setup as basic requirements | 26 |
| | 8.17.3 | Test article configuration | 26 |
| | 8.17.4 | Monitoring during test | 26 |
| | 8.17.5 | Test levels and duration | 26 |
| | 8.17.6 | Test conditions and guidelines | 26 |
| 8.18 | Acousti | ic test | 27 |
| | 8.18.1 | Purpose of test | 27 |
| | 8.18.2 | Test facilities and setup as basic requirements | 27 |
| | 8.18.3 | Test article configuration | 27 |
| | 8.18.4 | Monitoring during test | 27 |
| | 8.18.5 | Test levels and duration | 27 |
| | 8.18.6 | Test conditions and guidelines | 27 |
| 8.19 | Shock t | est | 27 |
| | 8.19.1 | Purpose of test | 27 |
| | 8.19.2 | Test facilities and setup as basic requirements | 27 |
| | 8.19.3 | Test article configuration | 27 |
| | 8.19.4 | Monitoring during test | 27 |
| | 8.19.5 | Test levels and duration | |
| | 8.19.6 | Test conditions and guidelines | 28 |
| 8.20 | Therma | al balance test | 28 |
| | 8.20.1 | Purpose of test | 28 |
| | 8.20.2 | Test facilities and setup as basic requirements | 28 |
| | 8.20.3 | Test article configuration | |
| | 8.20.4 | Monitoring during test | |
| | 8.20.5 | Test levels and duration | |
| | 8.20.6 | Test conditions and guidelines | |
| 8.21 | Therma | al vacuum test | |
| | 8.21.1 | Purpose of test | |
| | 8.21.2 | Test facilities and setup as basic requirements | |
| | 8.21.3 | Test article configuration | |
| | 8.21.4 | Monitoring during test | |
| | 8.21.5 | Test levels and duration | |
| | 8.21.6 | Test conditions and guidelines | |
| 8.22 | Functio | onal test in vacuum | |
| | | Purpose of test | |
| | 8.22.2 | Test facilities and setup as basic requirements | 30 |
| | 8.22.3 | Test article configuration | |
| | 8.22.4 | Monitoring during test | 30 |
| | 8.22.5 | Test levels and duration | |
| | 8.22.6 | Test conditions and guidelines | |
| 8.23 | Cold/H | ot start test | |
| | 8.23.1 | Purpose of test | 30 |
| | 8.23.2 | Test facilities and setup as basic requirements | 30 |
| | 8.23.3 | Test article configuration | |
| | 8.23.4 | Monitoring during test | 31 |
| | 8.23.5 | Test levels and duration | |
| | 8.23.6 | Test conditions and guidelines | 31 |
| 8.24 | Therma | al cycle functional test | 31 |
| | 8.24.1 | Purpose of test | |
| | 8.24.2 | Test facilities and setup as basic requirements | |
| | 8.24.3 | Test article configuration | |
| | 8.24.4 | Monitoring during test | |
| | 8.24.5 | Test levels and duration | |
| | 8.24.6 | Test conditions and guidelines | |
| 8.25 | Therma | al cycle endurance test | |
| | | Purpose of test | |
| | | | |

| | 8.25.2 Test facilities and setup as basic requirements | 32 |
|--------------|--|------------------|
| | 8.25.3 Test article configuration | |
| | 8.25.4 Monitoring during test | |
| | 8.25.5 Test levels and duration | |
| | 8.25.6 Test conditions and guidelines | |
| 8.26 | Pressure test | |
| 8.27 | Leakage test | |
| 8.28 | Microvibration test | |
| | 8.28.1 Purpose of test | |
| | 8.28.2 Test facilities and setup as basic requirements | |
| | 8.28.3 Test article configuration | |
| | 8.28.4 Monitoring during test | |
| | 8.28.5 Test levels and duration | |
| 0.20 | 8.28.6 Test conditions and guidelines | |
| 8.29 | Burn-in and wear-in test | |
| 8.30 | End-to-end mission simulation 8.30.1 Purpose of test | |
| | 8.30.1 Purpose of test | |
| | 8.30.3 Test article configuration | |
| | 8.30.4 Monitoring during test | |
| | 8.30.5 Test levels and duration | |
| | 8.30.6 Test conditions and guidelines | |
| 8.31 | Bake out and outgas test | |
| 0.01 | 8.31.1 Purpose of test | |
| | 8.31.2 Test facilities and setup as basic requirements | |
| | 8.31.3 Test article configuration | |
| | 8.31.4 Monitoring during test | |
| | 8.31.5 Test levels and duration | |
| | 8.31.6 Test conditions and guidelines | 35 |
| 8.32 | Tailoring and waiver guides | 36 |
| Annex A (no | ormative) Tailoring and waiver guides | 37 |
| Annex B (inf | formative) Basis of test levels and duration | 42 |
| Annex C (inf | formative) Design, verification and testing philosophy for sma | ll spacecrafts45 |
| Annex D (in | formative) Test selection logic flow | 68 |
| Annex E (inf | formative) Environment stress screening and burn-in | 80 |
| Annex F (inf | formative) Thermal vacuum or thermal cycle? | 81 |
| Bibliograph | ny | 84 |

Foreword

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